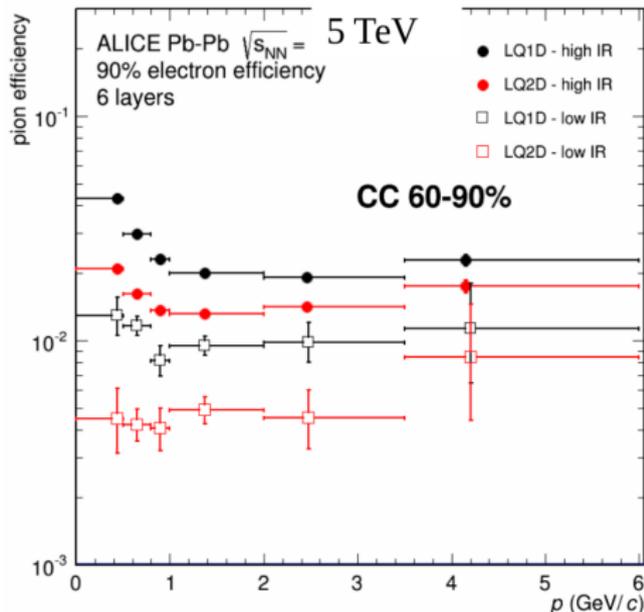
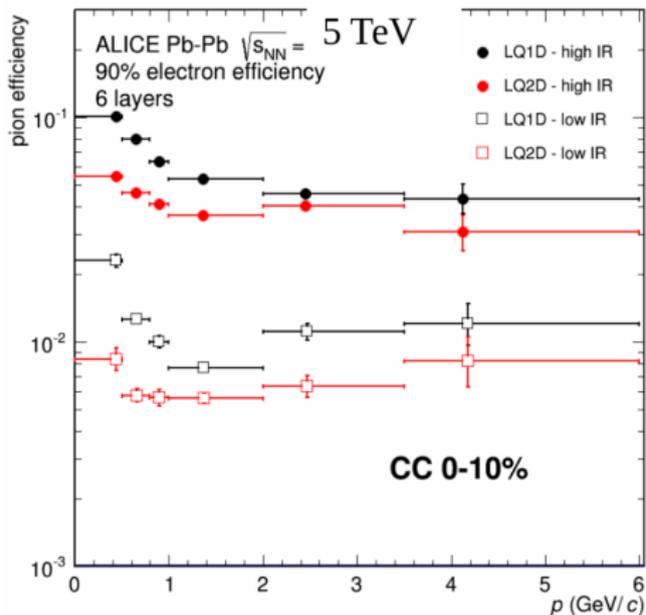


Generation of TRD PID Reference Parameters for PbPb @ 5.04 TeV (LHC15o)

Katharina Garner, Universität Münster
September 24, 2018

Problem: Performance Differing for High and Low IR



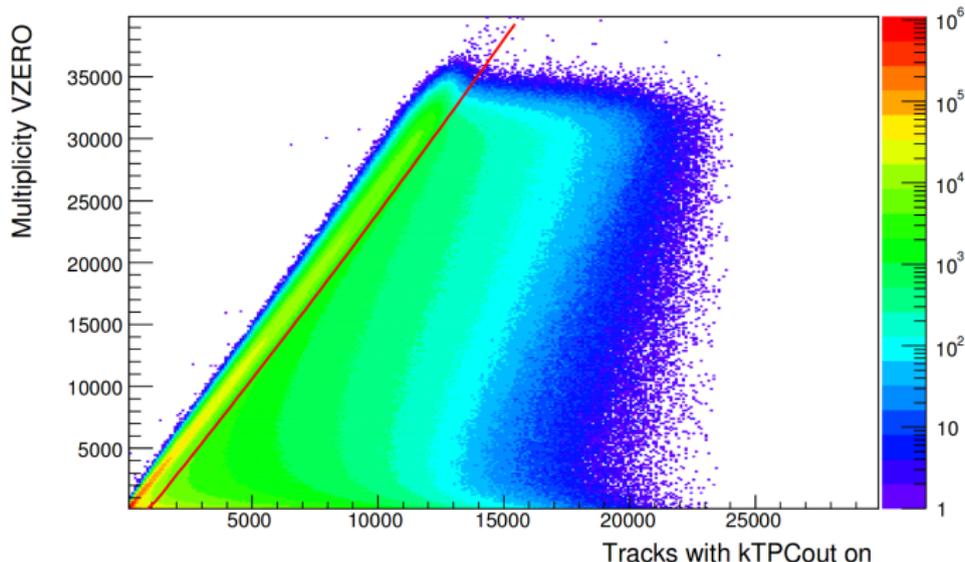
→ Introduce New Pile-Up Cut

(taken from https://indico.cern.ch/event/590505/contributions/2382007/attachments/1383299/2105525/Pachmayer_trdPID_Oslo.pdf, Y. Pachmayer)

Utilisation of Further Pile-Up Cut

- V0 has lower readout time than TPC thus TPC sees more pile-up
→ cut on multiplicity correlation of VZERO vs. TPCout
- exclude events towards the right of the red line defined by

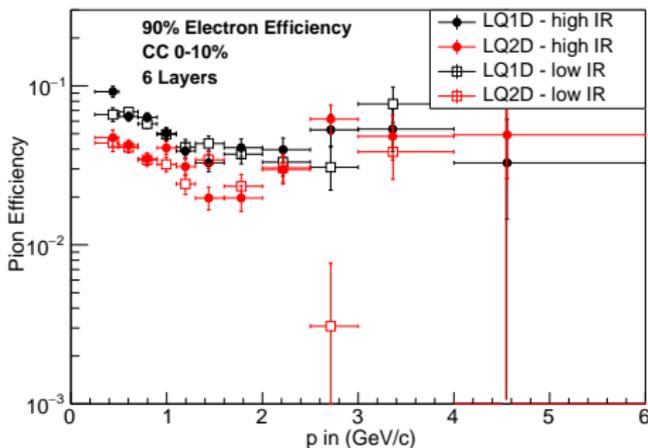
$$2 \cdot 10^{-5}(\text{kTPCout})^2 + 25(\text{kTPCout}) - 2200$$



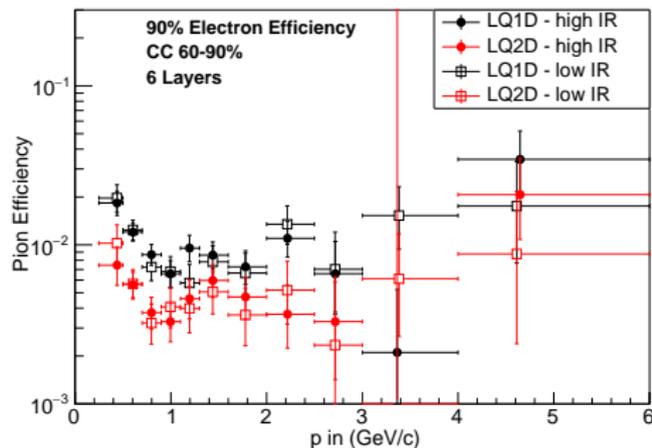
(taken from <https://alice-notes.web.cern.ch/node/592>, I.Arsene et al.)

Performance With Additional Pile-Up Cut

LQ1(2)D_5trl_C0_PionEffvsP



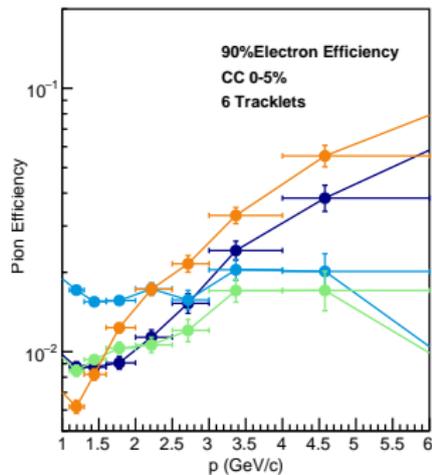
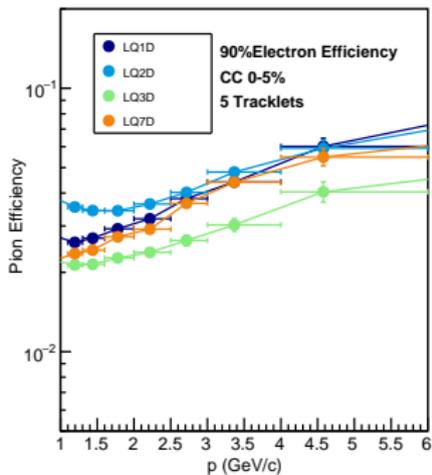
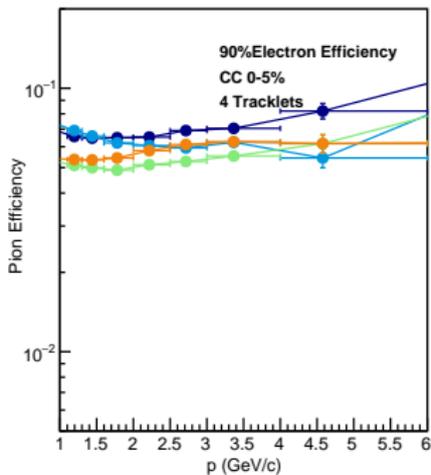
LQ1(2)D_5trl_C0_PionEffvsP



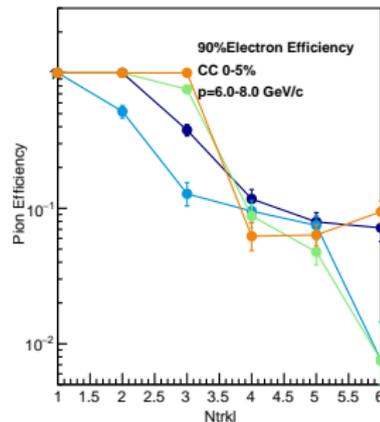
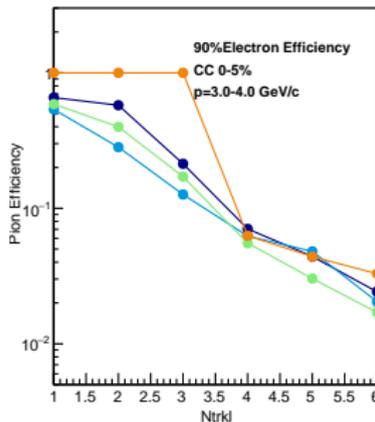
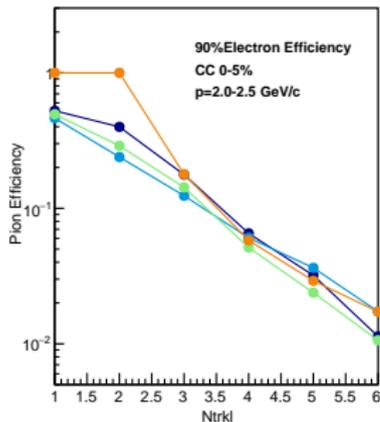
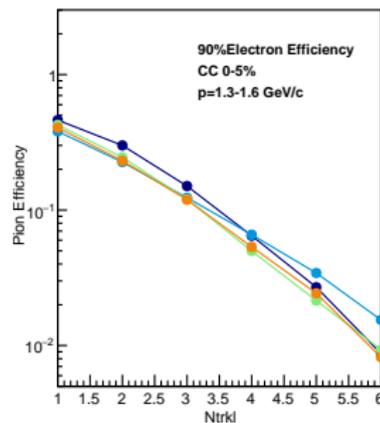
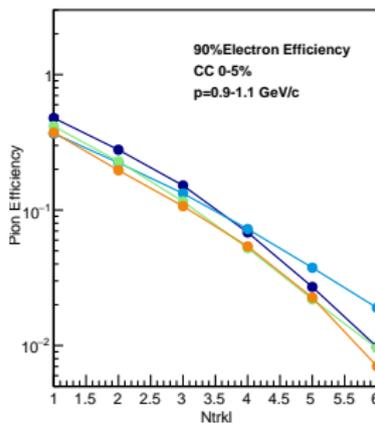
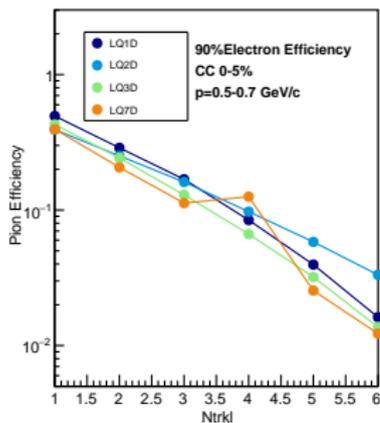
→ About 13 % of Event Multiplicity Cut Away
(highIR: 13.6 %, lowIR: 0.1 %)

→ Roughly 4 Mio Events for Parameter Generation

Performance wrt Particle Momentum



Performance wrt Number of Tracklets



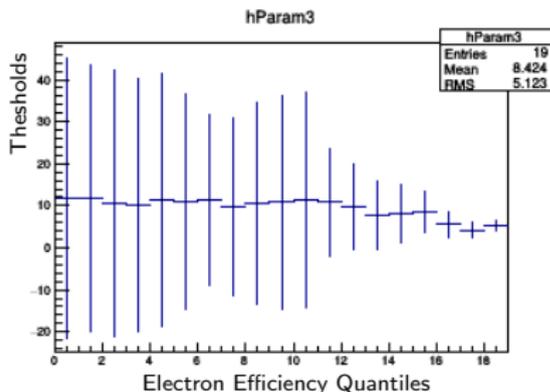
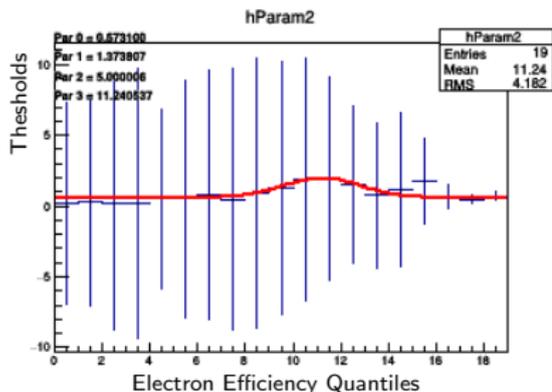
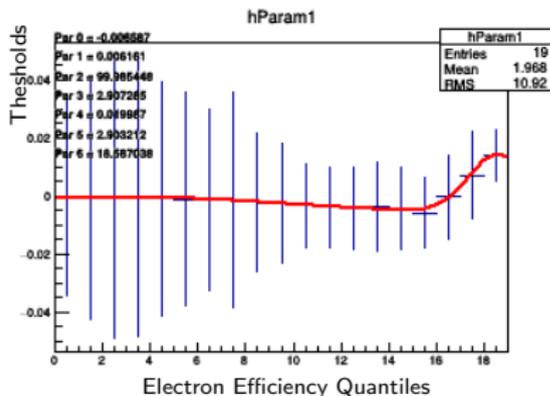
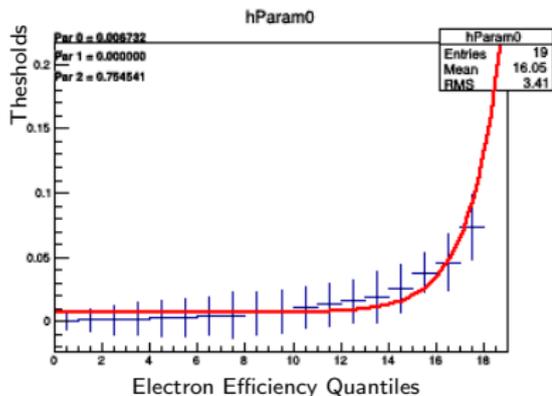
Generation of Threshold Parameters

- derive charge loss Q distribution for each particle species from pure particle sample
- interpret multiplicity at Q as probability $P(Q|e)$ that particle species loses Q
- for each momentum interval derive likelihood distribution

$$\mathcal{L}(e|Q) = \frac{P(Q|e)}{P(Q|e) + P(Q|\pi)}$$

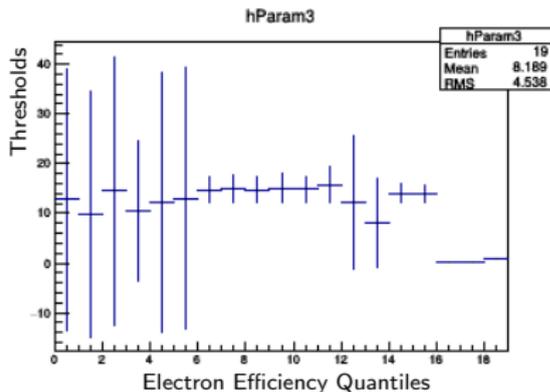
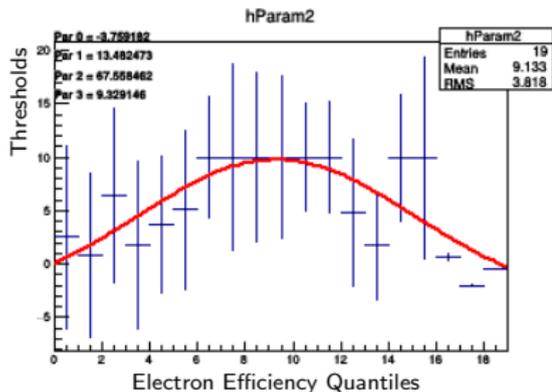
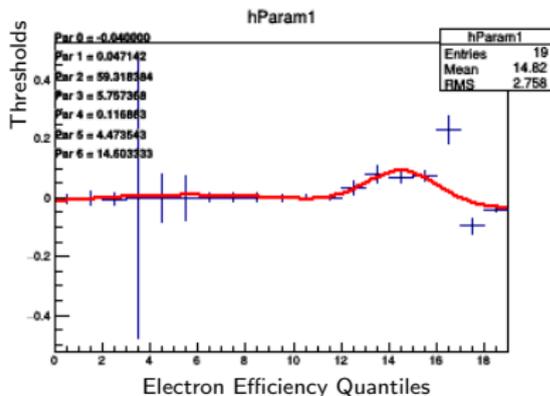
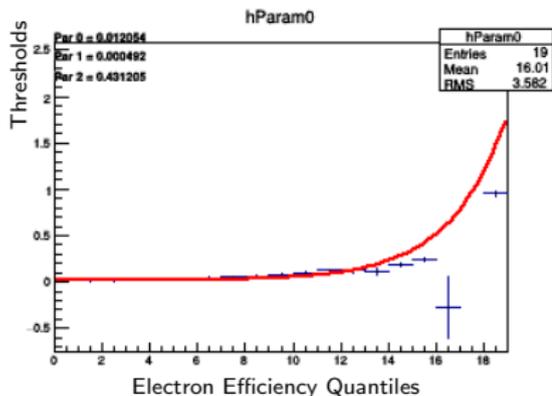
- derive thresholds determining at which $\mathcal{L}(e|Q)$ to cut to get certain electron efficiency
- store fit function for threshold values vs. p
→ sometimes large fit outliers

Testing New Fit Methods for Fit of Threshold Parameters



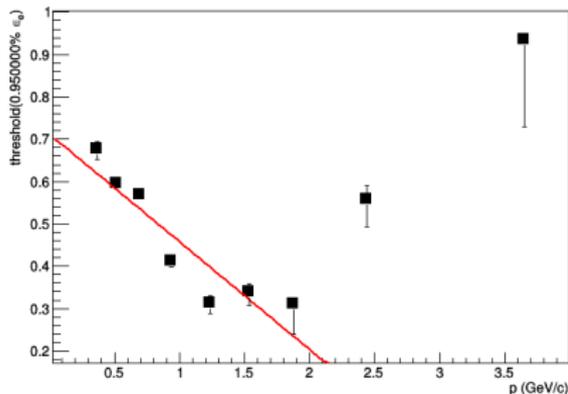
Threshold Fit Function: $f(p) = 1 - \text{Par0} - \text{Par1} \cdot p - \text{Par2} \cdot \exp(-\text{Par3} \cdot p)$

Testing New Fit Methods for Fit of Threshold Parameters

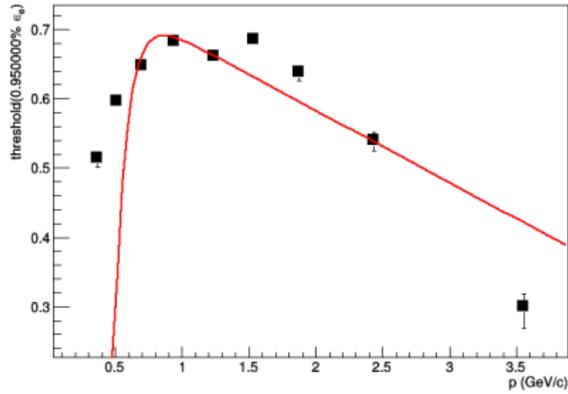


Threshold Fit Function: $f(p) = 1 - \text{Par0} - \text{Par1} \cdot p - \text{Par2} \cdot \exp(-\text{Par3} \cdot p)$

Testing New Fit Methods for Fit of Threshold Parameters



(3 Tracklets, LQ2D, CC=40-60%)



(5 Tracklets, LQ1D, CC=0-5%)

Ideas:

- fix fitparameters to parameters from fit of previous electron efficiency quantile
- fit fitparameters vs. electron efficiency quantiles; fit quantiles again and fix to result from fit to parameters
 - so far better χ^2 but less good performance but kept in mind

Summary

- new pile-up cut alignes performances for low and high interaction rates for LHC15o
→ TRD PID reference parameters soon uploaded to AliPhysics
- new fit methods for thresholds under investigation but so far less good performance

reconstruction passes:

high IR: pass1_pidfix

245232, 245231, 245152, 245151, 245146, 245145

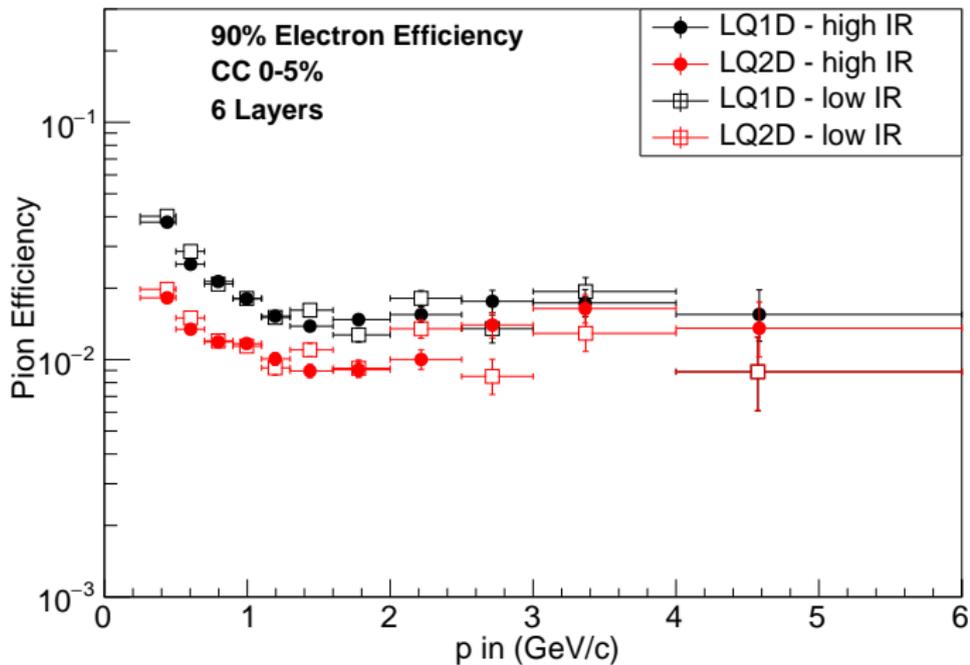
low IR: pass3_pidfix

244918, 244975, 244980, 244982, 244983, 245064, 245066, 245068,
246391, 246392

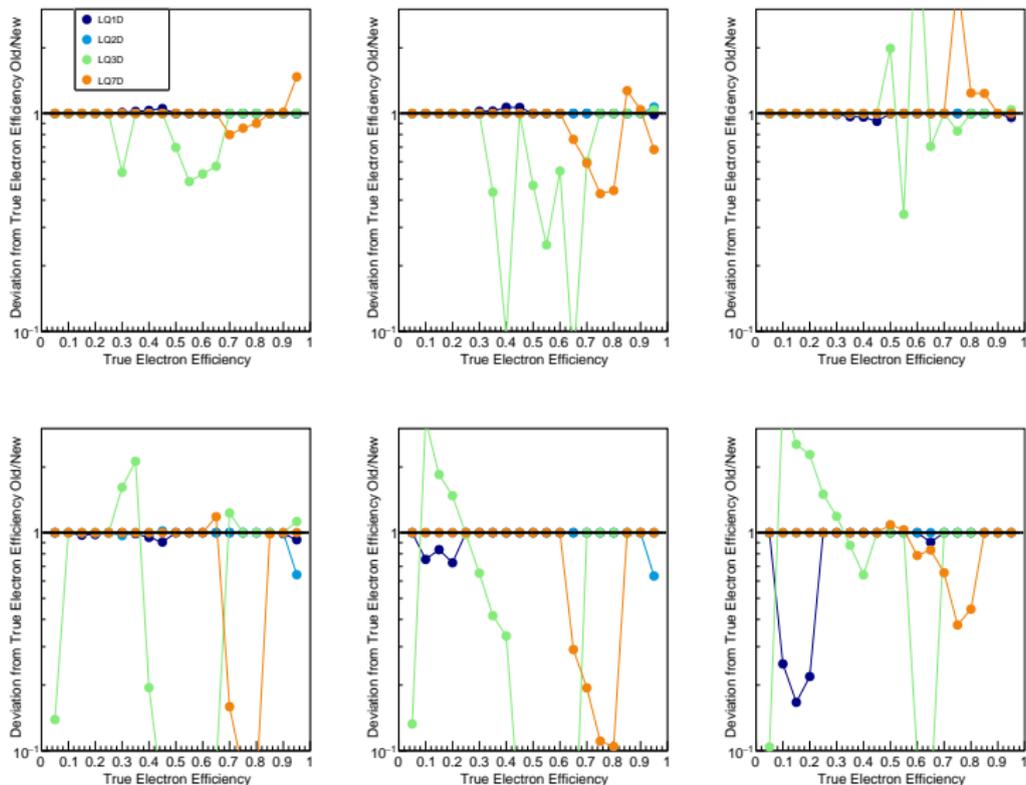
BACKUP

Performance With Additional Pile-Up Cut

LQ1(2)D_5trl_C0_PionEffvsP



Deviation: True Electron Efficiency for Old and New Threshold Fit Method



(values < 1 point to worse performance of new fit method)